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Fairchild Semiconductor NDT455N

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SEMICONDUCTOR TM

NDT455N N-Channel Enhancement Mode Field Effect Transistor

General Description

These N-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as DC motor control and DC/DC conversion where fast switching, low in-line power loss, and resistance to transients are needed.

Features

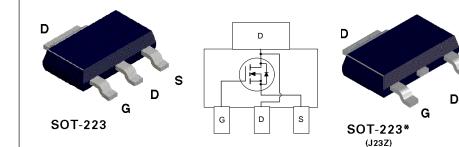
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.

S

G

D

s



Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		NDT455N	Units	
V _{DSS}	Drain-Source Voltage		30	V	
V _{GSS}	Gate-Source Voltage		20	V	
D	Drain Current - Continuous	(Note 1a)	± 11.5	А	
	- Pulsed		± 40		
P _D	Maximum Power Dissipation	(Note 1a)	3	W	
		(Note 1b)	1.3		
		(Note 1c)	1.1		
Γ _J ,T _{stg}	Operating and Storage Temperature Range	•	-65 to 150	°C	
THERMA	L CHARACTERISTICS				
۲ _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	42	°C/W	
۲ _{өлс}	Thermal Resistance, Junction-to-Case	(Note 1)	12	°C/W	

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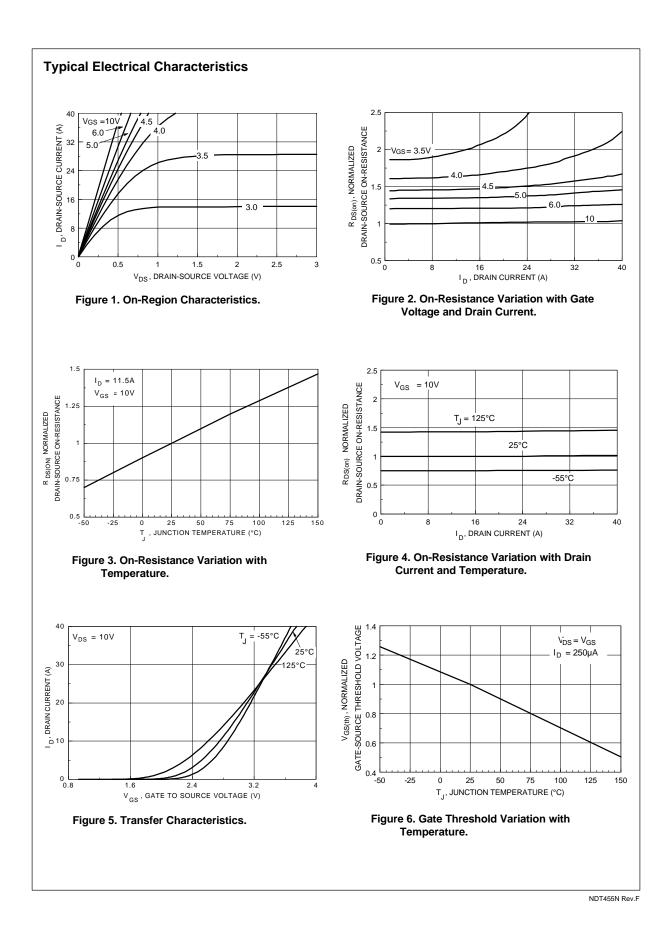
Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		30			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$				1	μA
			$T_J = 55^{\circ}C$			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$		1	1.5	3	V
			T _J = 125°C	0.7	0.9	2.2	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_{D} = 11.5 \text{ A}$	•		0.013	0.015	Ω
			T _J = 125°C		0.019	0.03	
		$V_{GS} = 4.5 \text{ V}, \ I_{D} = 10 \text{ A}$			0.018	0.02	
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$		30			Α
		$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		15			
g _{FS}	Forward Transconductance	$V_{GS} = 10 \text{ V}, I_{D} = 11.5 \text{ A}$			26		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 15, V_{GS} = 0 V,$			1220		pF
C _{oss}	Output Capacitance	f = 1.0 MHz			715		pF
C _{rss}	Reverse Transfer Capacitance				280		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 15 \text{ V}, \text{ I}_{D} = 1 \text{ A},$			11	20	ns
t,	Turn - On Rise Time	$V_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{GEN}} = 6 \Omega$			16	30	ns
t _{D(off)}	Turn - Off Delay Time				48	80	ns
t _r	Turn - Off Fall Time				40	70	ns
Q _g	Total Gate Charge	V _{DS} = 10 V,			43	61	nC
Q _{gs}	Gate-Source Charge	$I_{\rm D}^{\rm BC}$ = 11.5 A, V _{GS} = 10 V			4		nC
Q_{gd}	Gate-Drain Charge				11		nC



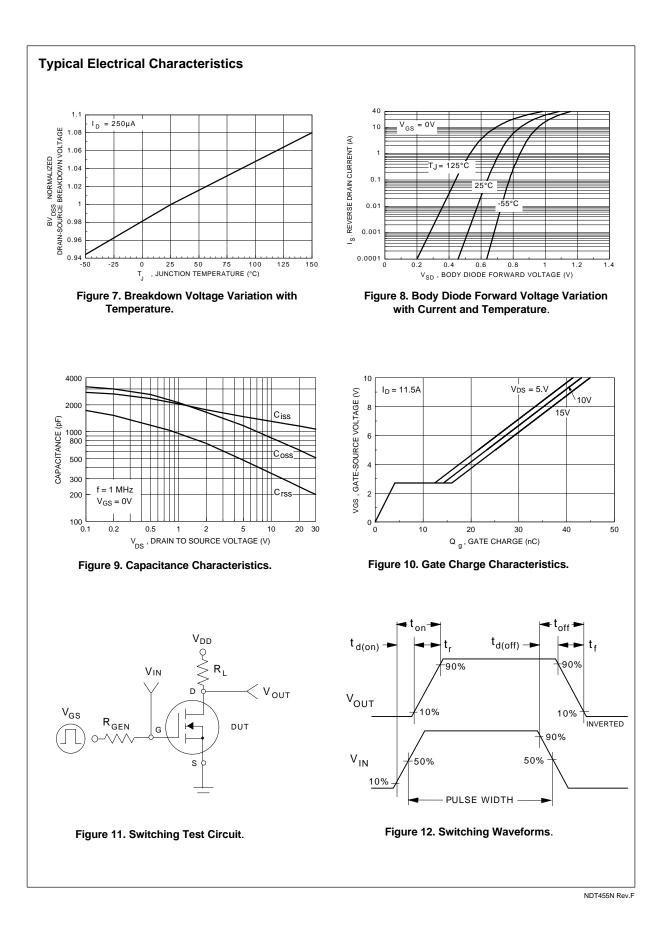
mbol	lectrical Characteristics (T _A = 25°C unless otherwise noted)					-
	Parameter	Conditions		Min Ty	p Max	Unit
RAIN-SC	URCE DIODE CHARACTERISTICS AN	D MAXIMUM RATINGS				
	Maximum Continuous Drain-Source Dio	de Forward Current			2.5	Α
)	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.5 A (Note 2)		0.84	45 1.2	V
	Reverse Recovery Time	$V_{GS} = 0 V, I_F = 2.5 A dI_F/dt = 100$	0 A/µs		140	ns
Solder mou R _{eli} a is four t c	$\begin{array}{c} \frac{r_{J}-r_{A}}{r_{\theta JA}(r)} = \frac{T_{J}-T_{A}}{R_{\theta JC}+R_{\theta CA}(r)} = I_{D}^{2}(t) \times R_{DS(ON) \oplus T_{J}} \ R_{\rm exis} \ \text{is t} \\ \text{inting surface of the drain pins. } R_{\rm exic} \ \text{is guaranteed by design} \\ \text{id to be:} \\ . 42^{\circ} CW \ \text{with 1 in}^{2} \ \text{of 2 oz copper mounting pad.} \\ . 55^{\circ} CW \ \text{with 0.066 in}^{2} \ \text{of 2 oz copper mounting pad.} \\ . 10^{\circ} CW \ \text{with 0.0123 in}^{2} \ \text{of 2 oz copper mounting pad.} \\ \end{array}$	he sum of the junction-to-case and case-to-ambien while R _{eck} is defined by users. For general referenc	t thermal resistance where the thermal resistance of the thermal the thermal resistance where the the thermal resistance where the the the the the the the the the the	FR-4 PCB under	I reference is defi	ned as th
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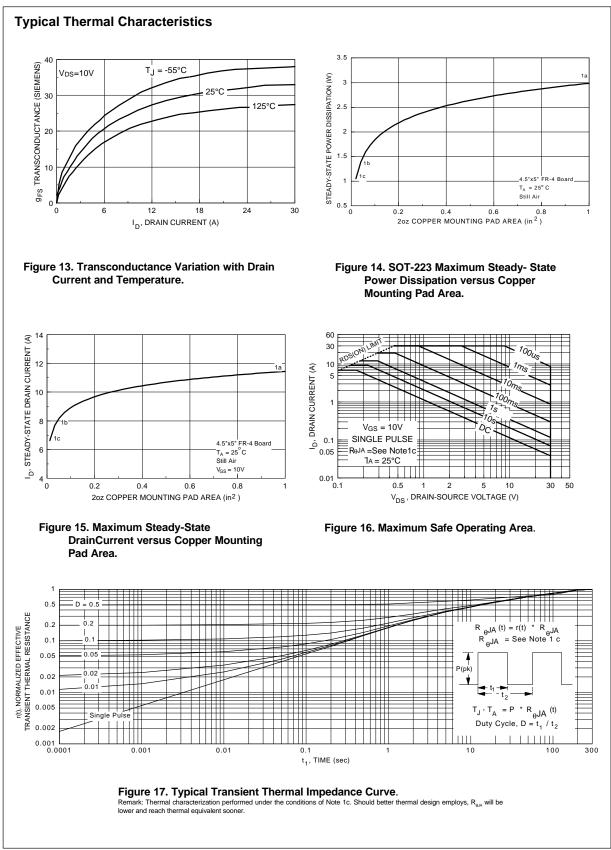












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